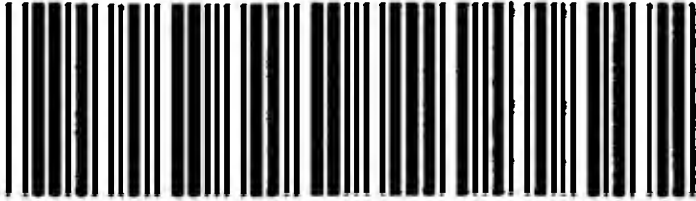


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,584	CHEN ET AL.	
	Examiner	Art Unit	
	Matthew G. Kayrish	2653	

SEARCHED			
Class	Subclass	Date	Examiner
720	610	12/5/2005	MK
720	610	12/6/2005	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	610	12/5/2005	MK
720	610	12/6/2005	MK
EAST (USPG-PUB)		12/6/2005	MK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search History)	11/18/2005	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search History)	11/22/2005	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search History)	11/23/2005	MK
EAST (USPG-PUB, USPAT, USOCR) (See Attached Search History)	11/29/2005	MK
EAST (EPO, JPO, IBM_TDB, DERWENT) (See Attached Search History)	11/23/2005	MK